Search Notes

App	lication/Control	No.

Applicant(s)/Patent under Reexamination

HAYASHI ET AL.

10/763,160

Examiner

Art Unit

Jin-Cheng Wang

2672

	SEARCHED		
Class	Subclass	Date	Examiner
345	629	5/22/2005	JCW
345	156	5/22/2005	JCM
715	790-791	5/22/2005	JCM
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